



## ISOLATED RS-485 PROFIBUS TRANSCEIVER

### FEATURES

- 4000-V<sub>PEAK</sub> Isolation
- Bus-Pin ESD Protection
  - 16 kV HBM Between Bus Pins and GND2
  - 6 kV HBM Between Bus Pins and GND1
- Meets or Exceeds the Requirements of EN 50170 and TIA/EIA-485
- Signaling Rates up to 40 Mbps
- Differential Output Exceeds 2.1 V (54 Ω Load)
- Low Bus Capacitance – 10 pF (MAX)

- 50 kV/μs Typical Transient Immunity
- Failsafe Receiver for Bus Open, Short, Idle
- 3.3-V Inputs are 5-V Tolerant

### APPLICATIONS

- Profibus
- Factory Automation
- Networked Sensors
- Motor/Motion Control
- HVA and Building Automation Networks
- Networked Security Stations

### DESCRIPTION

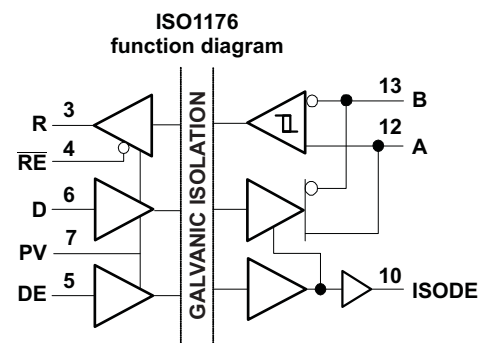
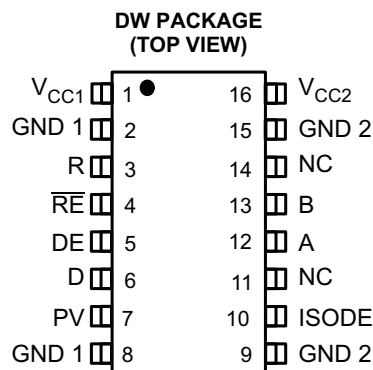
The ISO1176 is an isolated differential line transceiver designed for use in PROFIBUS applications. The device is ideal for long transmission lines since the ground loop is broken to provide for operation with a much larger common mode voltage range. The symmetrical isolation barrier of each device is tested to provide 2500 V<sub>rms</sub> of isolation between the line transceiver and the logic level interface.

The galvanically isolated differential bus transceiver is an integrated circuit designed for bi-directional data communication on multipoint bus-transmission lines. The transceiver combines a galvanically isolated differential line driver and differential input line receiver. The driver has an active-high enable with isolated enable-state output on the ISODE pin (pin 10) to facilitate direction control. The driver differential outputs and the receiver differential inputs connect internally to form a differential input/output (I/O) bus port that is designed to offer minimum loading to the bus whenever the driver is disabled or V<sub>cc2</sub> = 0.

The PV pin (pin 7) is provided as a full-chip enable option. All device outputs become high impedance when a logic low is applied to the PV pin. For more information, see the function tables in the device information section.

Any cabled I/O can be subjected to electrical noise transients from various sources. These noise transients can cause damage to the transceiver and/or near-by sensitive circuitry if they are of sufficient magnitude and duration. The ISO1176 can significantly reduce the risk of data corruption and damage to expensive control circuits.

The device is characterized for operation over the ambient temperature range of –40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

## ABSOLUTE MAXIMUM RATINGS

over operating junction temperature range unless otherwise noted<sup>(1)</sup>

				VALUE	UNIT	
$V_{CC1}$ , $V_{CC2}$	Supply voltage <sup>(2)</sup>			-0.5 to 7	V	
$V_O$	Voltage at any bus I/O terminal			-9 to 14	V	
$V_I$	Voltage input at any D, DE or $\overline{RE}$ terminal			-0.5 to 7	V	
$I_O$	Receiver output current			$\pm 10$	mA	
ESD	Electrostatic discharge	Human Body Model	JEDEC Standard 22, Test Method A114-C.01	Bus pins to GND1	$\pm 6$	kV
				Bus pins to GND2	$\pm 16$	
		Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	$\pm 4$	
				All pins	$\pm 1$	
Machine model	ANSI/ESDS5.2-1996	All pins	$\pm 200$	V		
$T_J$	Maximum junction temperature			170	$^{\circ}\text{C}$	

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. All voltage values are with respect to the network ground terminal unless otherwise noted.
- (2) All voltage values except differential I/O bus voltages are with respect to the referenced network ground terminal and are peak voltage values.

## RECOMMENDED OPERATING CONDITIONS

			MIN	TYP	MAX	UNIT
$V_{CC}$	Logic side supply voltage, $V_{CC1}$ (with respect to GND1)		3.15		5.5	V
	Bus side supply voltage, $V_{CC2}$ (with respect to GND2)		4.75		5.25	
$V_{CM}$	Voltage at either bus I/O terminal	A, B	-7		12	V
$V_{IH}$	High-level input voltage	PV, $\overline{RE}$			$V_{CC1}$	V
		D, DE	$0.7 V_{CC1}$			
$V_{IL}$	Low-level input voltage	PV, $\overline{RE}$	0		0.8	V
		D, DE			$0.3 V_{CC1}$	
$V_{ID}$	Differential input voltage	A with respect to B	-12		12	V
$I_O$	Output current	Driver	-70		70	mA
		Receiver	-8		8	
$T_J$	Operating junction temperature		-40		150	$\Omega$

## SUPPLY CURRENT

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$I_{CC1}$	Logic side RMS supply current	3 V	DE at 0 V			4	6	mA
			DE at $V_{CC1}$ , 2 Mbps			5		
			DE at $V_{CC1}$ , 25 Mbps			6		
		5.5 V	DE at 0 V			7	10	mA
			DE at $V_{CC1}$ , 2 Mbps			8		
			DE at $V_{CC1}$ , 25 Mbps			11		
$I_{CC2}$	Bus side RMS supply current	5.25 V	DE at 0 V			15	18	mA
			DE at $V_{CC1}$ , 2 Mbps, 54 $\Omega$ load			70		
			DE at $V_{CC1}$ , 25 Mbps, 54 $\Omega$ load			75		

## ISODE-PIN ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>OH</sub>	High-level output voltage	I <sub>OH</sub> = –8 mA	V <sub>CC2</sub> – 0.8	4.6		V
		I <sub>OH</sub> = –20 μA	V <sub>CC2</sub> – 0.1	5		
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 8 mA		0.2	0.4	V
		I <sub>OL</sub> = 20 μA		0	0.1	

## DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
V <sub>OD</sub>	Open-circuit differential output voltage	V <sub>A</sub> – V <sub>B</sub>  , <a href="#">Figure 1</a>	1.5		V <sub>CC2</sub>	V	
V <sub>OD(SS)</sub>	Steady-state differential output voltage magnitude	See <a href="#">Figure 2</a> and <a href="#">Figure 6</a>	2.1			V	
		Common-mode loading with V <sub>test</sub> from –7 V to 12 V, See <a href="#">Figure 3</a>	2.1				
ΔV <sub>OD(SS)</sub>	Change in steady-state differential output voltage between logic states	R <sub>L</sub> = 54 Ω, See <a href="#">Figure 4</a> and <a href="#">Figure 5</a>	–0.2		0.2	V	
V <sub>OC(SS)</sub>	Steady-state common-mode output voltage	R <sub>L</sub> = 54 Ω, See <a href="#">Figure 4</a> and <a href="#">Figure 5</a>		2	3	V	
ΔV <sub>OC(SS)</sub>	Change in steady-state common-mode output voltage		–0.2		0.2		
V <sub>OC(PP)</sub>	Peak-to-peak common-mode output voltage				0.5		
V <sub>OD(RING)</sub>	Differential output voltage over and under shoot	See <a href="#">Figure 6</a> and <a href="#">Figure 10</a>			10%	V <sub>OD(PP)</sub>	
V <sub>I(HYS)</sub>	Input voltage hysteresis	See <a href="#">Figure 7</a>		150		mV	
I <sub>I</sub>	Input current	D, DE at 0 V or V <sub>CC1</sub>	–10		10	μA	
		PV <sup>(1)</sup> at 0 V or V <sub>CC1</sub>			120		
I <sub>O(OFF)</sub>	Output current with power off	V <sub>CC</sub> ≤ 2.5 V	See Receiver input current				
I <sub>OZ</sub>	High impedance state output current	DE at 0 V					
I <sub>OS(P)</sub>	Peak short-circuit output current	DE at V <sub>CC</sub> , See <a href="#">Figure 8</a> and <a href="#">Figure 9</a>	V <sub>OS</sub> = –7 V to 12 V	–250	250	mA	
I <sub>OS(SS)</sub>	Steady-state short-circuit output current		V <sub>OS</sub> = 12 V, D at GND1				135
			V <sub>OS</sub> = –7 V, D at V <sub>CC1</sub>	–135			
C <sub>OD</sub>	Differential output capacitance		See Receiver C <sub>IN</sub>				
CMTI	Common-mode transient immunity	See <a href="#">Figure 20</a>	25			kV/μs	

(1) The PV pin has a 50 kΩ pull-up resistor and leakage current depends on supply voltage.

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## DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
$t_{pLH}$ , $t_{pHL}$	Propagation delay time	See Figure 10			35	ns	
$t_{sk(p)}$	Pulse skew ( $ t_{pHL} - t_{pLH} $ )		$V_{CC1}$ at 5 V $V_{CC2}$ at 5 V		2	5	ns
$t_{pLH}$ , $t_{pHL}$	Propagation delay time		$V_{CC1}$ at 3.3 V $V_{CC2}$ at 5 V			40	ns
$t_{sk(p)}$	Pulse skew ( $ t_{pHL} - t_{pLH} $ )				2	5	ns
$t_r$	Differential output signal rise time			2	3	7.5	ns
$t_f$	Differential output signal fall time			2	3	7.5	ns
$t_{pDE}$	DE to ISODE prop delay	See Figure 14			30	ns	
$t_{t(MLH)}$ , $t_{f(MLH)}$	Output transition skew	See Figure 11			1	ns	
$t_{p(AZH)}$ , $t_{p(BZH)}$ $t_{p(AZL)}$ , $t_{p(BZL)}$	Propagation delay time, high-impedance-to-active output	$C_L = 50$ pF, $\overline{RE}$ at 0 V, See Figure 12 and Figure 13			80	ns	
$t_{p(AHZ)}$ , $t_{p(BHZ)}$ $t_{p(ALZ)}$ , $t_{p(BLZ)}$	Propagation delay time, active-to- high-impedance output				80	ns	
$ t_{p(AZL)} - t_{p(BZH)} $ $ t_{p(AZH)} - t_{p(BZL)} $	Enable skew time			0.55	1.5	ns	
$t_{(CFB)}$	Time from application of short-circuit to current foldback		See Figure 9		0.5	$\mu$ s	
$t_{(TSD)}$	Time from application of short-circuit to thermal shutdown	$T_A = 25^\circ\text{C}$ , See Figure 9	100		$\mu$ s		

## RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
$V_{IT(+)}$	Positive-going differential input voltage threshold	See Figure 15		-80	-10	mV	
$V_{IT(-)}$	Negative-going differential input voltage threshold		$I_O = 8$ mA	-200	-120	mV	
$V_{hys}$	Hysteresis voltage ( $V_{IT+} - V_{IT-}$ )			40		mV	
$V_{OH}$	High-level output voltage	$V_{CC1}$ at 3.3 V and $V_{CC2}$ at 5 V	$V_{ID} = 200$ mV, See Figure 15	$I_{OH} = -8$ mA	$V_{CC1} - 0.4$	3	V
$V_{OL}$	Low-level output voltage		$V_{ID} = -200$ mV, See Figure 15	$I_{OH} = -20$ $\mu$ A $I_{OL} = 8$ mA $I_{OL} = 20$ $\mu$ A	$V_{CC1} - 0.1$	3.3	0.2 0.4 0 0.1
$V_{OH}$	High-level output voltage	$V_{CC1}$ at 5 V and $V_{CC2}$ at 5 V	$V_{ID} = 200$ mV, See Figure 15	$I_{OH} = -8$ mA	$V_{CC1} - 0.8$	4.6	V
$V_{OL}$	Low-level output voltage		$V_{ID} = -200$ mV, See Figure 15	$I_{OH} = -20$ $\mu$ A $I_{OL} = 8$ mA $I_{OL} = -20$ $\mu$ A	$V_{CC1} - 0.1$	5	0.2 0.4 0 0.1
$I_{A}$ , $I_{B}$ $I_{A(OFF)}$ $I_{B(OFF)}$	Bus pin input current	$V_I = -7$ V or 12 V, Other input = 0 V	$V_{CC} = 4.75$ V or 5.25 V $V_{CC2} = 0$ V		-160	200	$\mu$ A
$I_I$	Receiver enable input current	$\overline{RE} = 0$ V		-50	50	$\mu$ A	
$I_{OZ}$	High-impedance state output current	$\overline{RE} = V_{CC1}$		-1	1	$\mu$ A	
$R_{ID}$	Differential input resistance	A, B		48		k $\Omega$	
$C_{ID}$	Differential input capacitance	Test input signal is a 1.5 MHz sine wave with 1 $V_{pp}$ amplitude, $C_D$ is measured across A and B		7	10	pF	
$C_{MR}$	Common mode rejection	See Figure 19		4		V	

### RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
$t_{pLH}$ , $t_{pHL}$	Propagation delay time	See Figure 16			50	ns	
$t_{sk(p)}$	Pulse skew ( $ t_{pHL} - t_{pLH} $ )			2	5		
$t_{pLH}$ , $t_{pHL}$	Propagation delay time		See Figure 16			55	ns
$t_{sk(p)}$	Pulse skew ( $ t_{pHL} - t_{pLH} $ )				2	5	
$t_r$	Output signal rise time			2	4	ns	
$t_f$	Output signal fall time			2	4		
$t_{pZH}$	Propagation delay time, high-impedance-to-high-level output	DE at $V_{CC1}$ , See Figure 17		13	25	ns	
$t_{pHZ}$	Propagation delay time, high-level-to-high-impedance output			13	25		
$t_{pZL}$	Propagation delay time, high-impedance-to-low-level output	DE at $V_{CC}$ , See Figure 18		13	25	ns	
$t_{pLZ}$	Propagation delay time, low-level-to-high-impedance output			13	25		

### PARAMETER MEASUREMENT INFORMATION

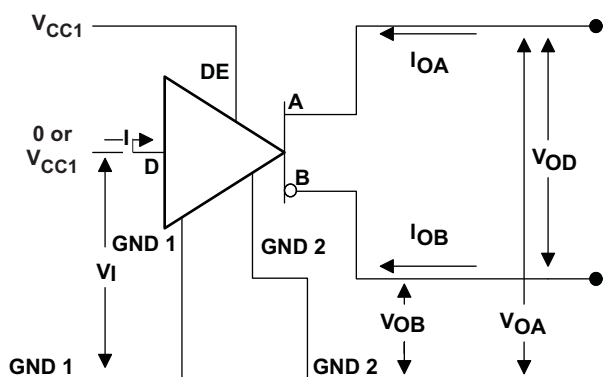


Figure 1. Open Circuit Voltage Test Circuit

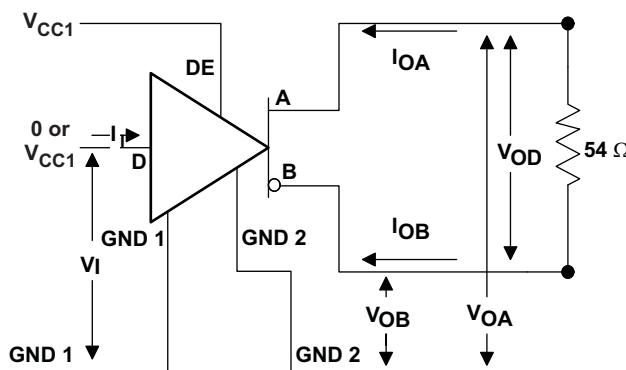


Figure 2.  $V_{OD}$  Test Circuit

PARAMETER MEASUREMENT INFORMATION (continued)

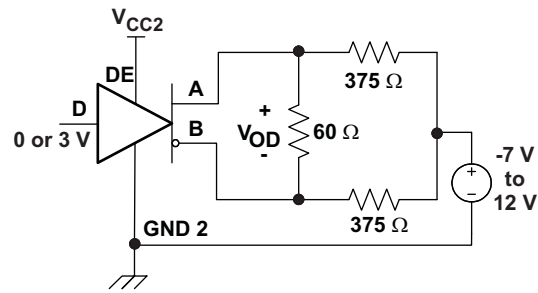


Figure 3. Driver  $V_{OD}$  with Common-mode Loading Test Circuit

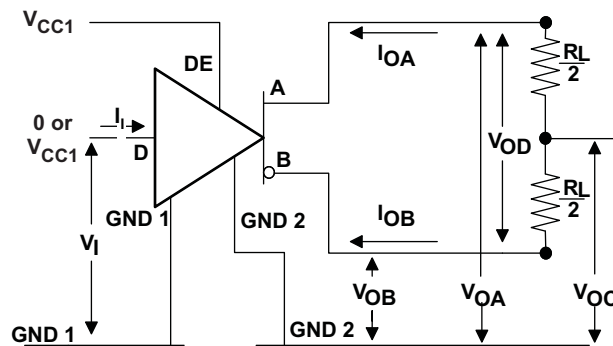


Figure 4. Driver  $V_{OD}$  and  $V_{OC}$  Without Common-Mode Loading Test Circuit

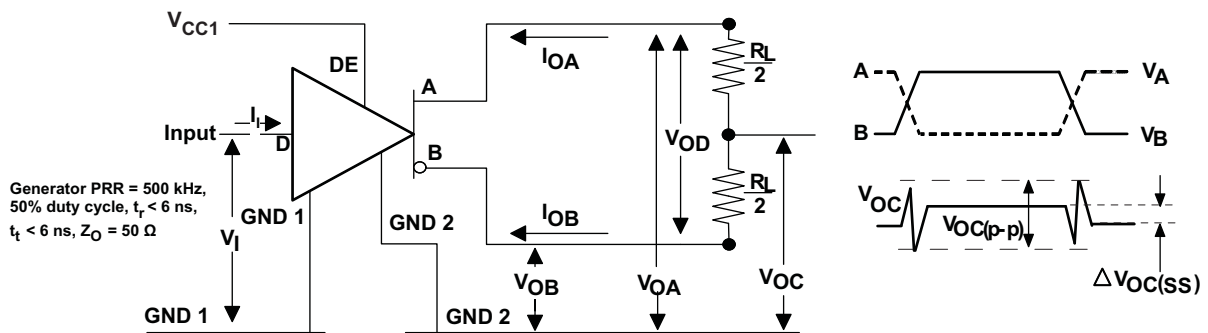


Figure 5. Steady-State Output Voltage Test Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION (continued)

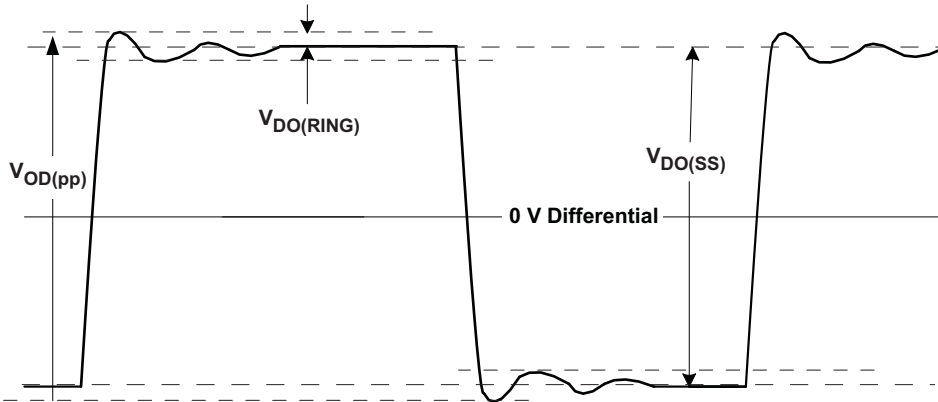


Figure 6.  $V_{OD(RING)}$  Waveform and Definitions

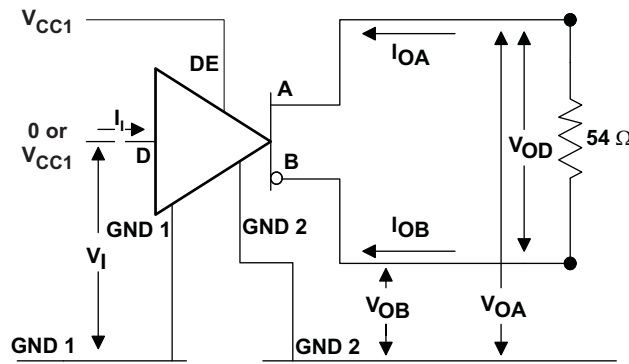


Figure 7. Input Voltage Hysteresis Test Circuit

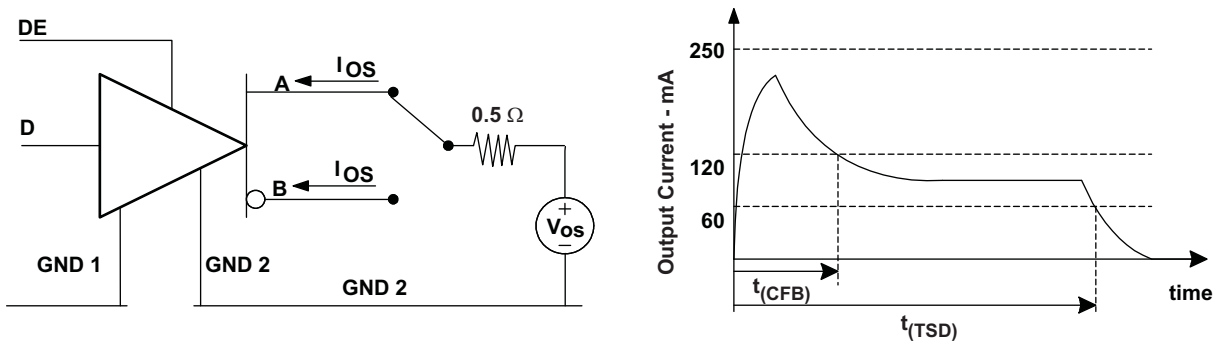


Figure 8. Driver Short-Circuit Test Circuit and Waveforms (Short Circuit applied at Time  $t=0$ )

PARAMETER MEASUREMENT INFORMATION (continued)

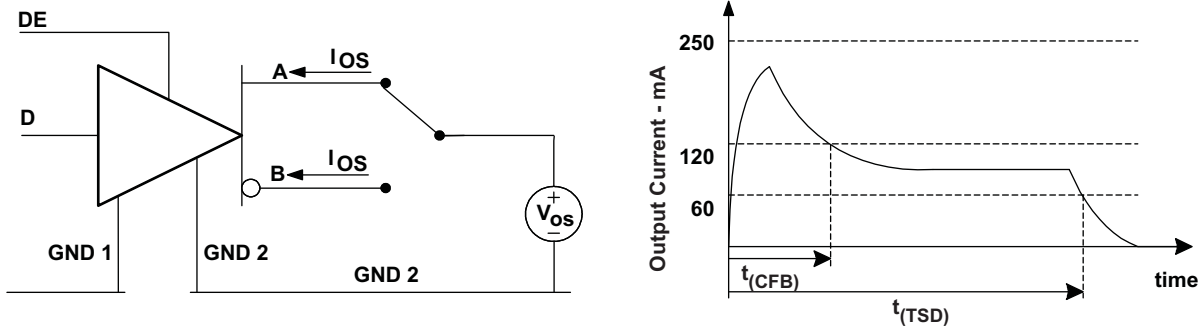


Figure 9.  $I_{OS(SS)}$  Steady State Short Circuit Output Current Test Circuit

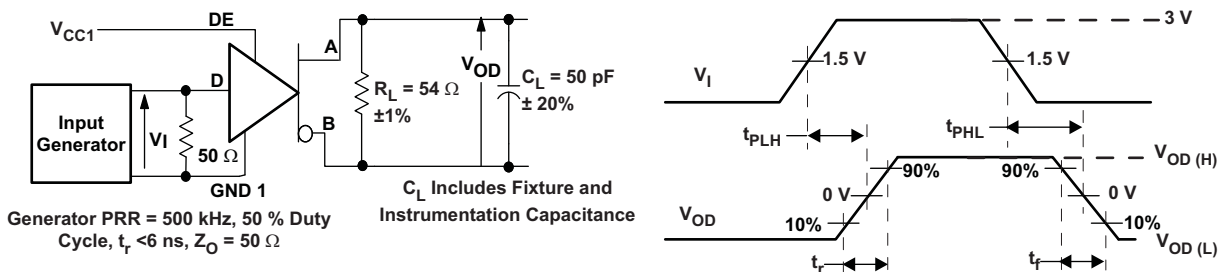


Figure 10. Driver Switching Test Circuit and Waveforms

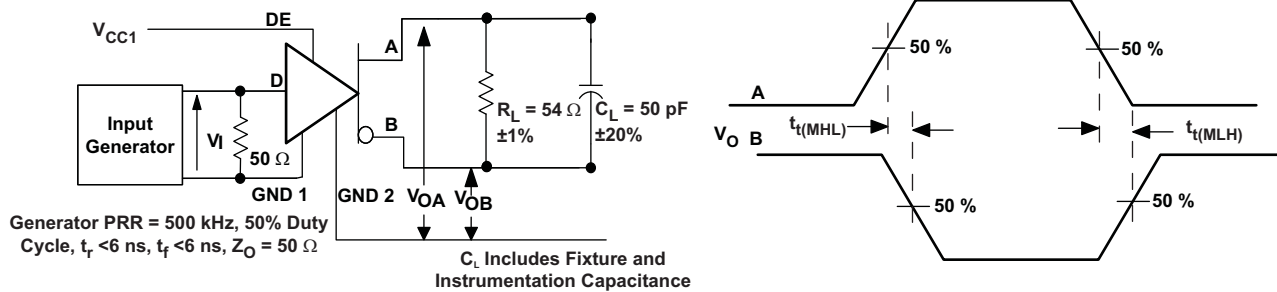


Figure 11. Driver Output Transition Skew Test Circuit and Waveforms

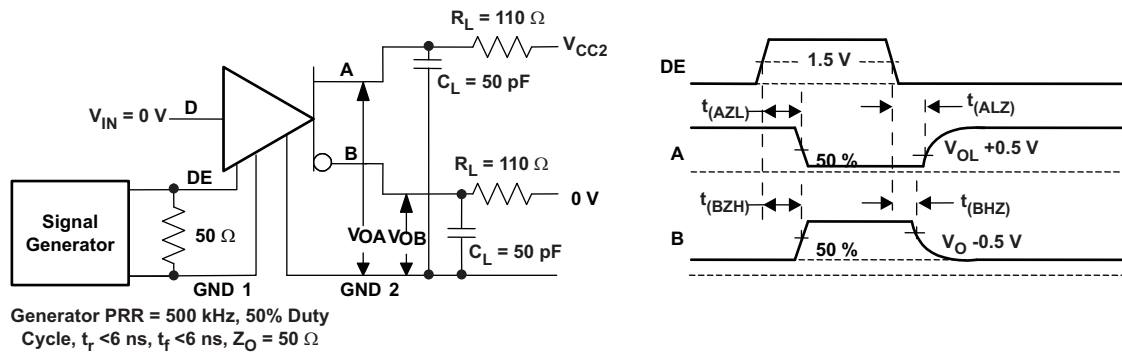


Figure 12. Driver Enable/Disable Test, D at Logic Low Test Circuit and Waveforms



PARAMETER MEASUREMENT INFORMATION (continued)

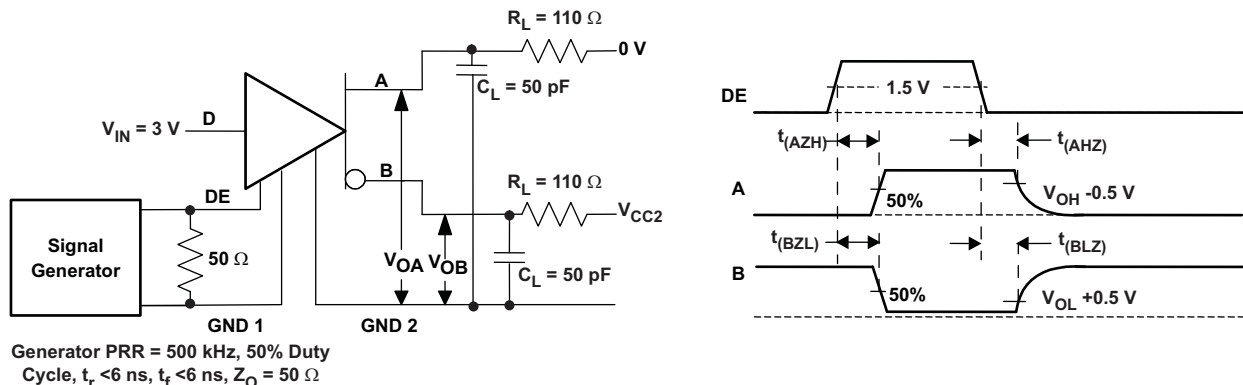


Figure 13. Driver Enable/Disable Test, D at Logic High Test Circuit and Waveforms

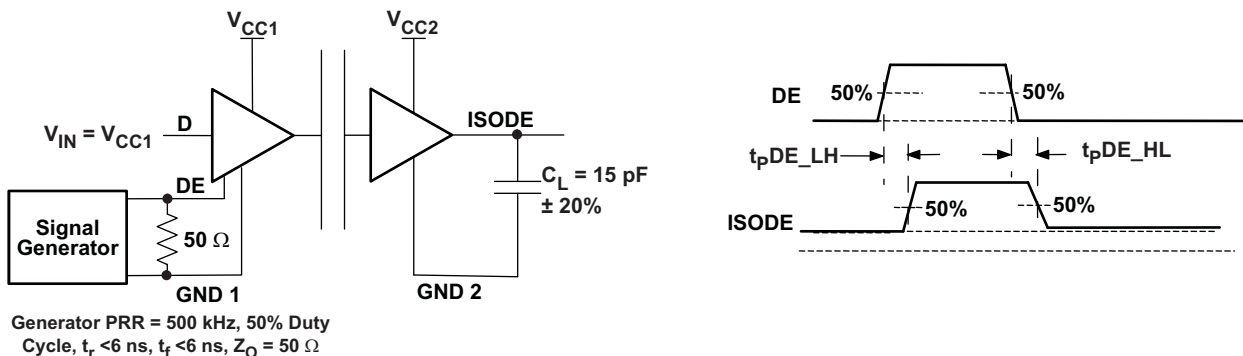


Figure 14. DE to ISODE Prop Delay Test Circuit and Waveforms

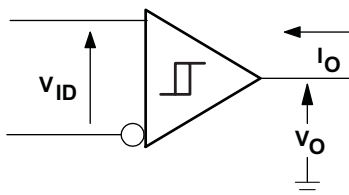


Figure 15. Receiver DC Parameter Definitions

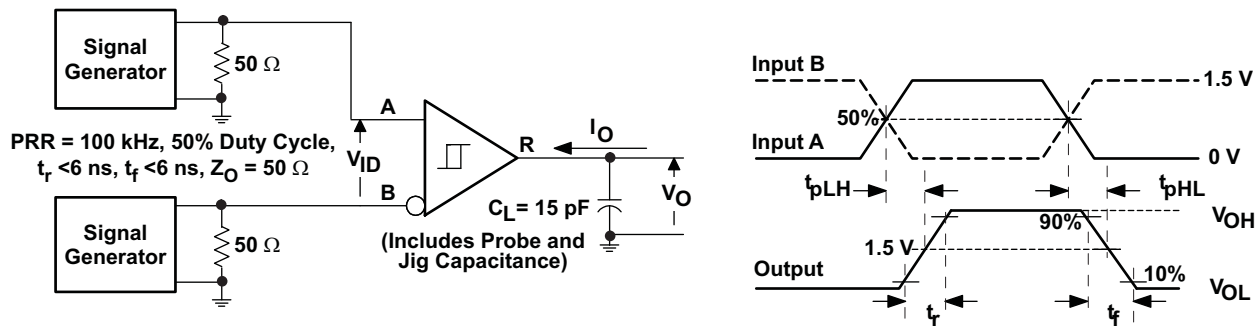


Figure 16. Receiver Switching Test Circuit and Waveforms

PARAMETER MEASUREMENT INFORMATION (continued)

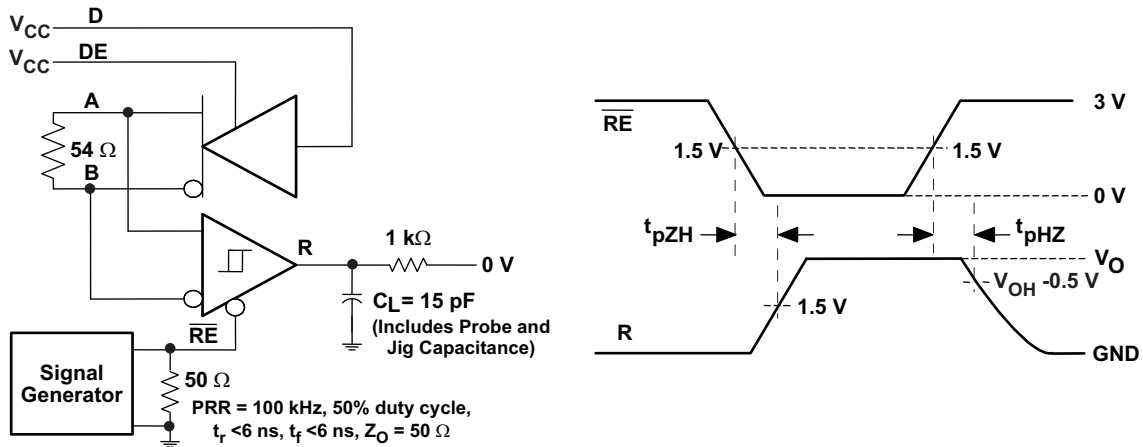


Figure 17. Receiver Enable Test Circuit and Waveforms, Data Output High

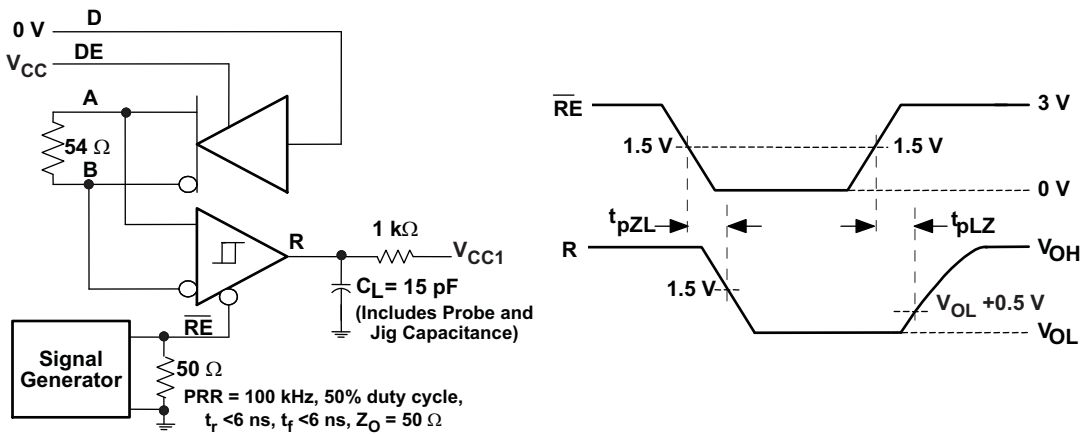


Figure 18. Receiver Enable Test Circuit and Waveforms, Data Output Low

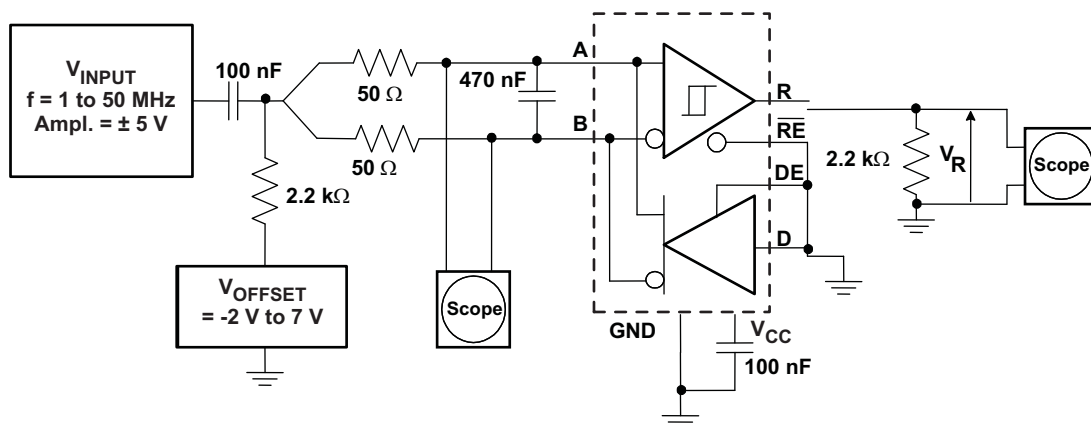


Figure 19. Common-Mode Rejection Test Circuit

PARAMETER MEASUREMENT INFORMATION (continued)

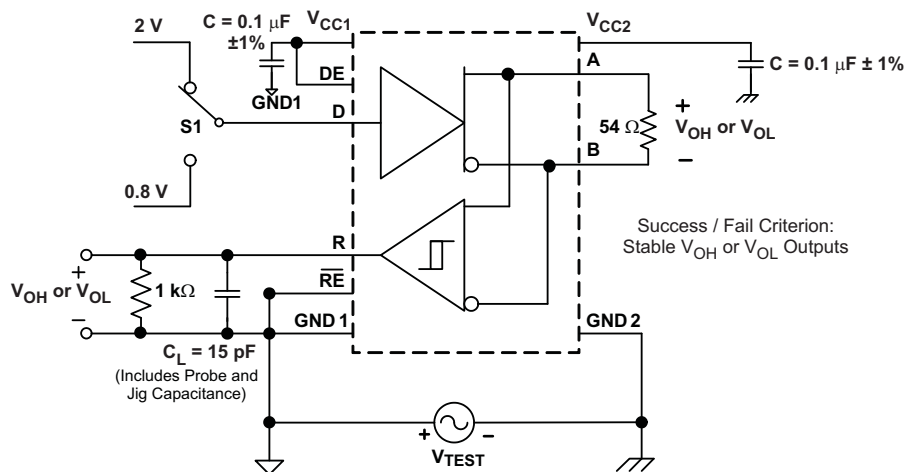


Figure 20. Common-Mode Transient Immunity Test Circuit

TYPICAL CHARACTERISTICS

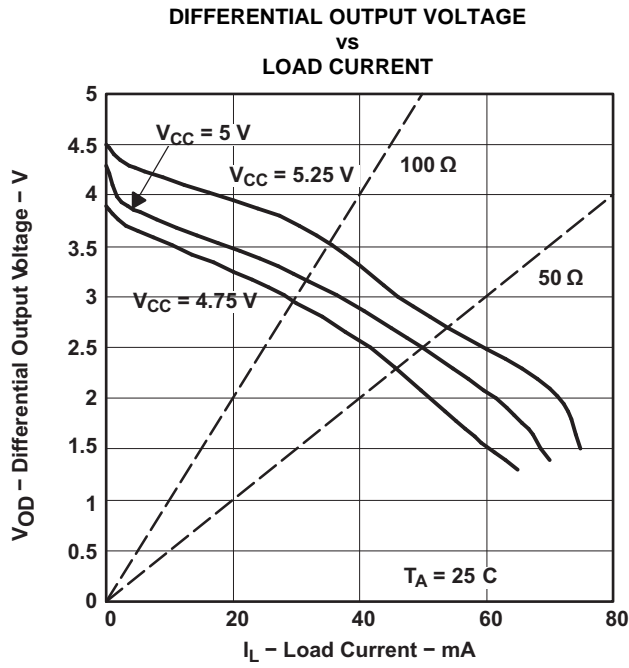


Figure 21.

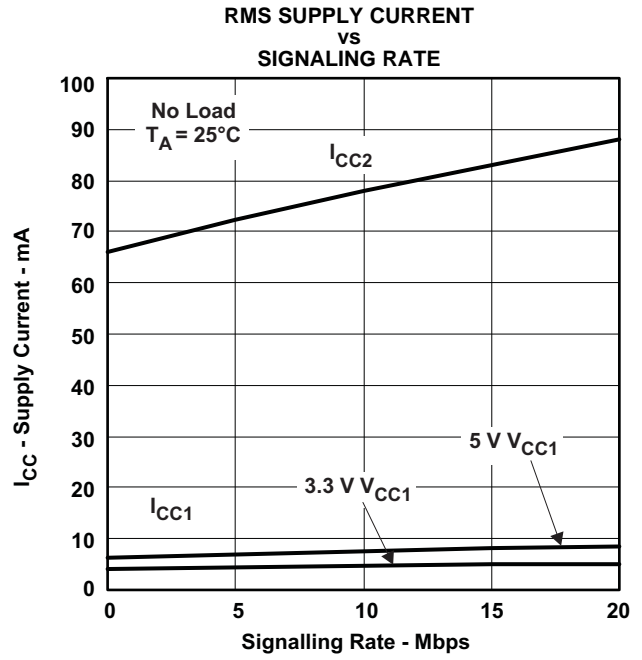


Figure 22.

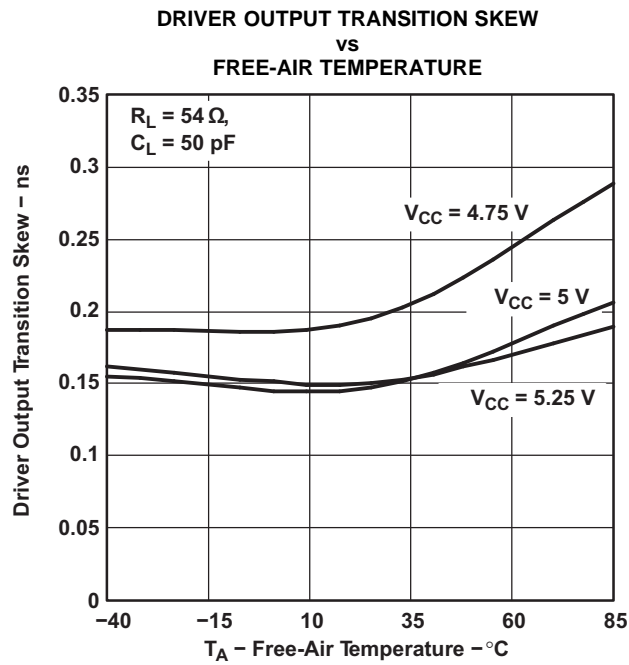


Figure 23.

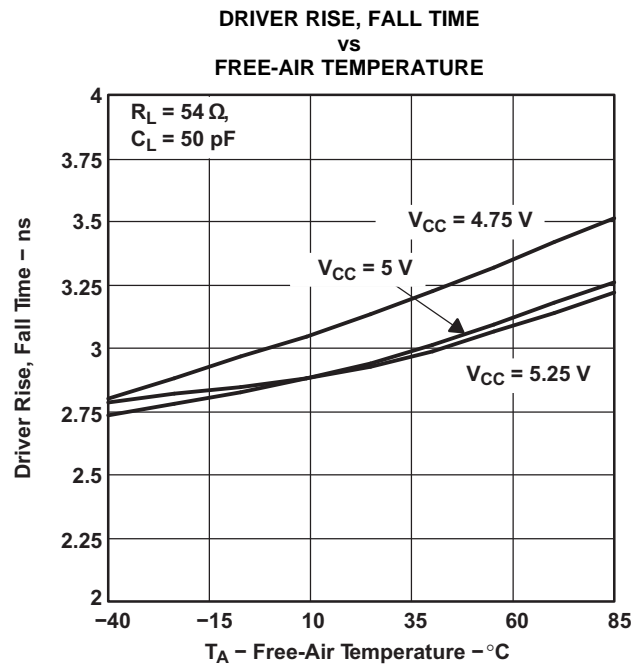


Figure 24.

TYPICAL CHARACTERISTICS (continued)

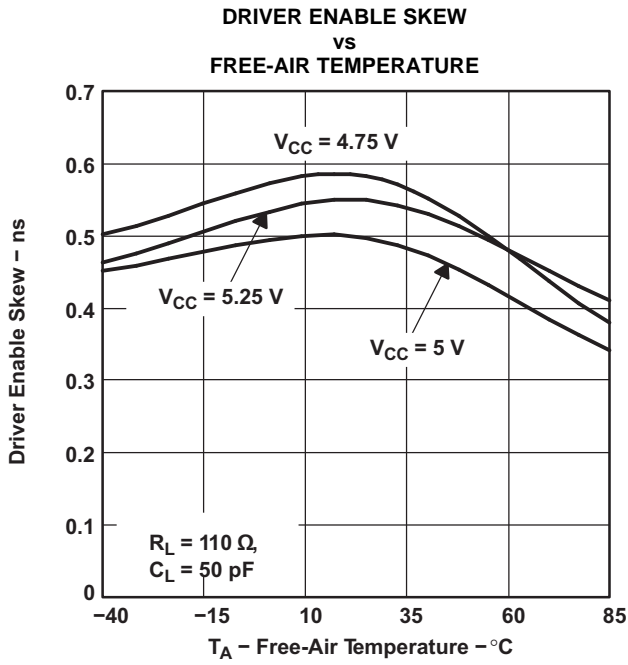


Figure 25.

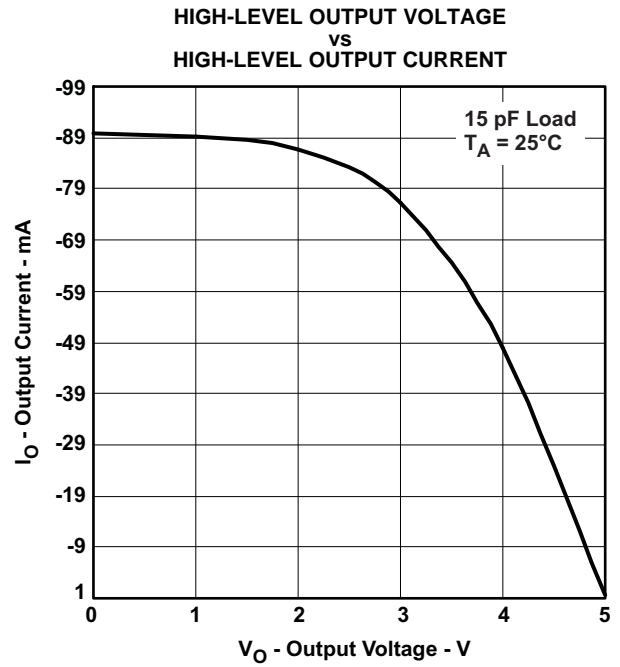


Figure 26.

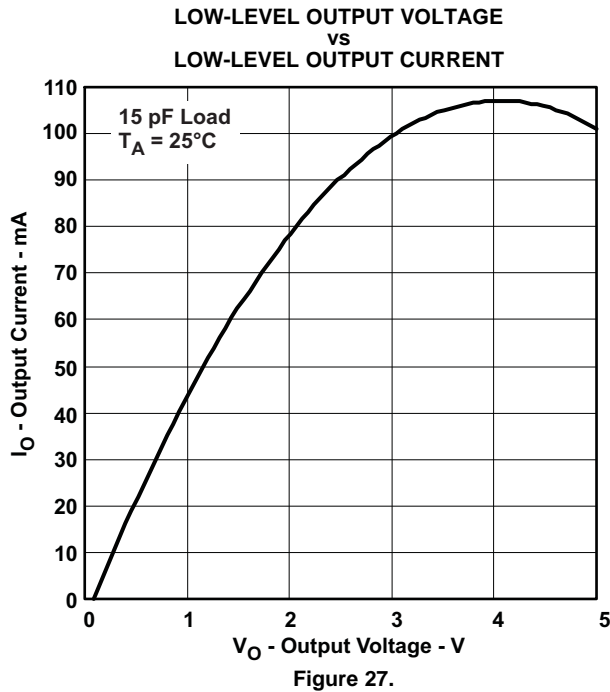


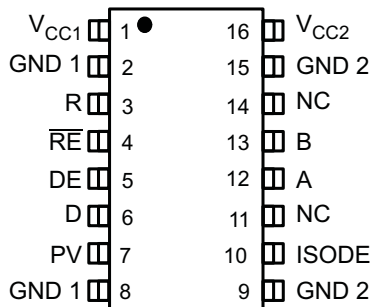
Figure 27.

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## DEVICE INFORMATION

**DW PACKAGE  
(TOP VIEW)**


## PACKAGE PIN FUNCTION DESCRIPTION

NAME	PIN NO.	FUNCTION
Vcc1	1	logic side power supply
GND1	2, 8	logic side ground, internally connected
R	3	receiver output
$\overline{RE}$	4	receiver logic-low enable
DE	5	driver logic-high enable input
D	6	driver input
PV	7	ISO1176 chip enable, logic high applied immediately after power-up for device operation. A logic low 3-states all outputs.
GND2	9, 15	bus side ground, internally connected
ISODE	10	bus-side driver enable output
nc	11, 14	not connected internally, may be left floating
A	12	non-inverting bus output
B	13	inverting bus output
Vcc2	16	bus side power supply

**DRIVER FUNCTION TABLE**

V <sub>CC1</sub>	V <sub>CC2</sub>	POWER VALID (PV) (ISO1176)	INPUT (D)	ENABLE INPUT (DE)	ENABLE OUTPUT (ISODE)	OUTPUTS	
						A	B
PU	PU	H or open	H	H	H	H	L
PU	PU	H or open	L	H	H	L	H
PU	PU	H or open	X	L	L	Z	Z
PU	PU	H or open	X	open	L	Z	Z
PU	PU	H or open	open	H	H	H	L
PD	PU	X	X	X	L	Z	Z
PU	PD	X	X	X	L	Z	Z
PD	PD	X	X	X	L	Z	Z
X	X	L	X	X	L	Z	Z

H = high level, L= low level, X = don't care, Z = high impedance (off), ? = indeterminate

**RECEIVER FUNCTION TABLE**

V <sub>CC1</sub>	V <sub>CC2</sub>	POWER VALID (PV) (ISO1176)	DIFFERENTIAL INPUT V <sub>ID</sub> = (V <sub>A</sub> – V <sub>B</sub> )	ENABLE ( $\overline{RE}$ )	OUTPUT )
PU	PU	H or open	$-0.01\text{ V} \leq V_{ID}$	L	H
PU	PU	H or open	$-0.2\text{ V} < V_{ID} < -0.01\text{ V}$	L	?
PU	PU	H or open	$V_{ID} \leq -0.2\text{ V}$	L	L
PU	PU	H or open	X	H	Z
PU	PU	H or open	X	open	Z
PU	PU	H or open	Open circuit	L	H
PU	PU	H or open	Short Circuit	L	H
PU	PU	H or open	Idle (terminated) bus	L	H
PD	PU	X	X	X	Z
PU	PD	H or open	X	L	H
PD	PD	X	X	X	Z
X	X	L	X	X	Z

H = high level, L= low level, X = don't care, Z = high impedance (off), ? = indeterminate

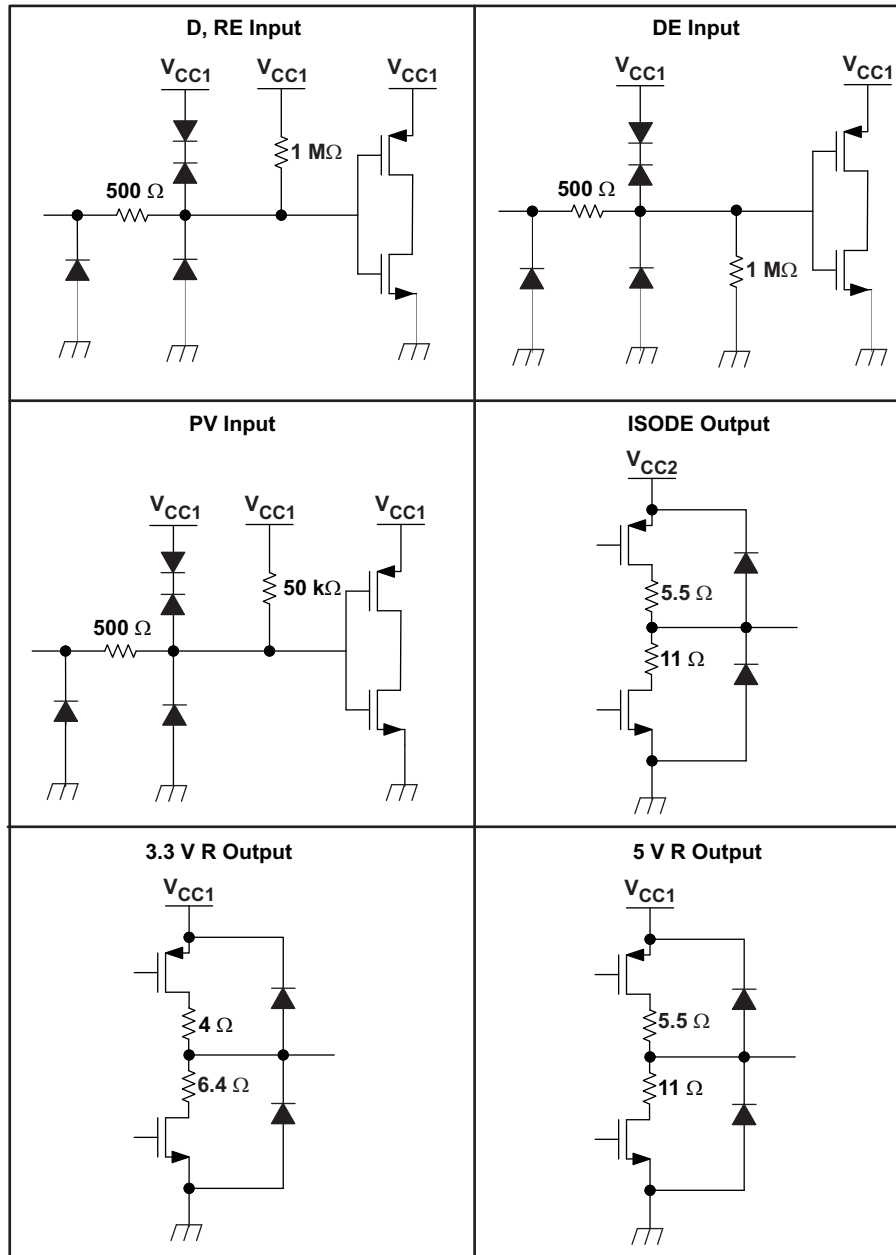
# ISO1176

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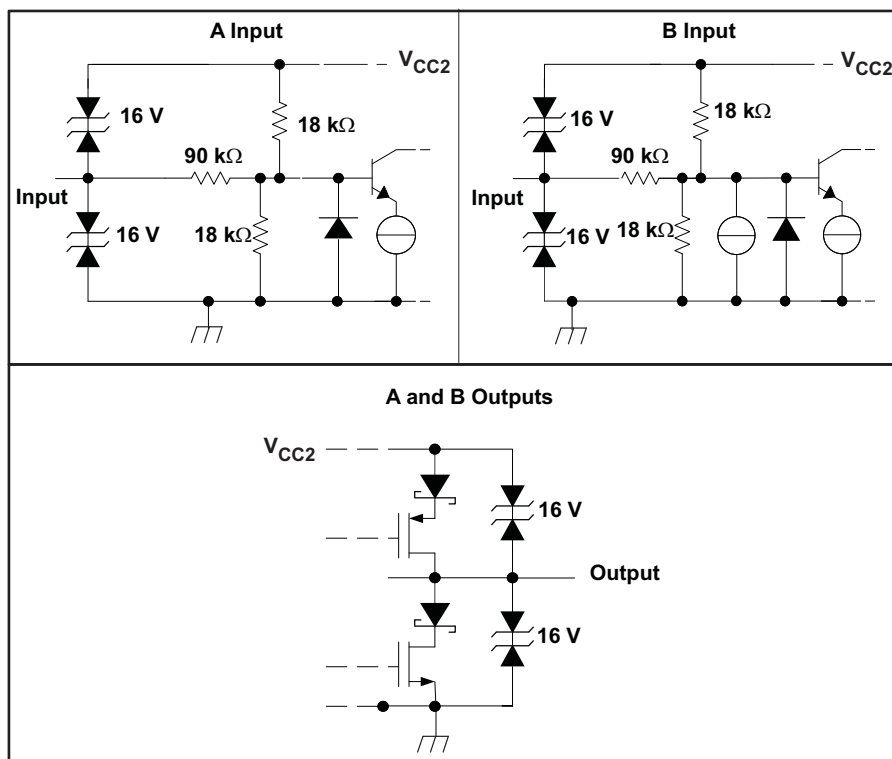
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## EQUIVALENT CIRCUIT SCHEMATICS







### IEC SAFETY LIMITING VALUES

Safety limiting intends to prevent potential damage to the isolation barrier upon failure of input or output circuitry. A Failure of the IO can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures.

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_S$	Safety input, output, or supply current	DW-16	$\theta_{JA} = 212^\circ\text{C/W}$ , $V_I = 5.5\text{ V}$ , $T_J = 170^\circ\text{C}$ , $T_A = 25^\circ\text{C}$			128	mA
$T_S$	Maximum case temperature	DW-16				150	$^\circ\text{C}$

The safety-limiting constraint is the absolute maximum junction temperature specified in the absolute maximum ratings table. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determines the junction temperature. The assumed junction-to-air thermal resistance in the Thermal Characteristics table is that of a device installed in the JESD51-3, Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages and is conservative. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.

# ISO1176

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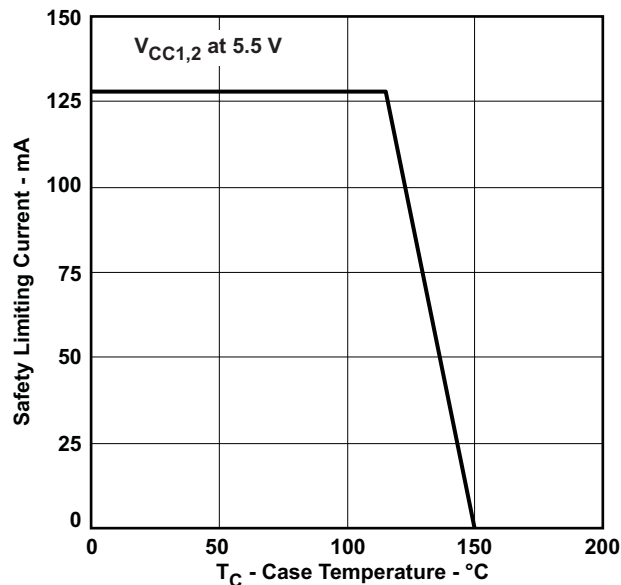
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## THERMAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$\theta_{JA}$	Junction-to-air	Low-K thermal resistance <sup>(1)</sup>		168		°C/W
		High-K board <sup>(1)</sup>		96.1		
$\theta_{JB}$	Junction-to-board thermal resistance			61		°C/W
$\theta_{JC}$	Junction-to-case thermal resistance			48		°C/W
$P_D$	Device power dissipation	$V_{CC1} = V_{CC2} = 5.25\text{ V}$ , $T_J = 150^\circ\text{C}$ , $C_L = 15\text{ pF}$ , Input a 20 MHz 50% duty cycle square wave			220	mW

(1) Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.


 Figure 28. DW-16  $\theta_{JC}$  Thermal Derating Curve per IEC 60747-5-2

## PACKAGE CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (Clearance)	Shortest terminal to terminal distance through air	8.34			mm
L(I02)	Minimum external tracking (Creepage) <sup>(1)</sup>	Shortest terminal to terminal distance across the package surface	8.1			mm
CTI	Tracking resistance (Comparative Tracking Index)	DIN IEC 60112 / VDE 0303 Part 1	$\geq 175$			V
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.008			mm
$R_{IO}$	Isolation resistance	Input to output, $V_{IO} = 500\text{ V}$ , all pins on each side of the barrier tied together creating a two-terminal device		$>10^{12}$		$\Omega$
$C_{IO}$	Barrier capacitance Input to output	$V_I = 0.4 \sin(4E6\pi t)$		2		pF
$C_I$	Input capacitance to ground	$V_I = 0.4 \sin(4E6\pi t)$		2		pF

(1) Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed circuit board do not reduce this distance.

Creepage and clearance on a printed circuit board become equal according to the measurement techniques shown in the Isolation Glossary. Techniques such as inserting grooves and/or ribs on a printed circuit board are used to help increase these specifications.

## REGULATORY INFORMATION

VDE	UL
Certified according to IEC 60747-5-2	Recognized under 1577 Component Recognition Program <sup>(1)</sup>
File Number: 40014131	File Number: E181974

(1) Production tested  $\geq 3000$  Vrms for 1 second in accordance with UL 1577.

## IEC 60554-1 RATINGS TABLE

PARAMETER	TEST CONDITIONS	SPECIFICATION
Basic isolation group	Material group	IIIa
Installation classification	Rated mains voltage < 150 VRMS	I-IV
	Rated mains voltage < 300 VRMS	I-III
	Rated mains voltage < 400 VRMS	I-II

## IEC 60747-5-2 INSULATION CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	SPECIFICATION	UNIT
$V_{IORM}$	Maximum working insulation voltage		560	V
$V_{PR}$	Input to output test voltage	Method b1, $V_{PR} = V_{IORM} \times 1.875$ , 100% Production test with $t = 1$ s, Partial discharge <5 pC	1050	V
$V_{IOTM}$	Transient overvoltage	$t = 60$ s	4000	V
$R_S$	Insulation resistance	$V_{IO} = 500$ V at $T_S$	$>10^9$	$\Omega$
	Pollution degree		2	

## APPLICATION INFORMATION

### Transient Voltages

Isolating of a circuit insulates it from other circuits and earth, so that noise voltage develops across the insulation rather than circuit components. The most common noise threat to data-line circuits is voltage surges or electrical fast transients that occur after installation. The transient ratings of the ISO1176 standard are sufficient for all but the most severe installations. However, some equipment manufacturers use ESD generators to test equipment transient susceptibility. This practice can easily exceed insulation ratings. ESD generators simulate static discharges that may occur during device or equipment handling with low-energy but very high-voltage transients.

Figure 29 models the ISO1176 bus IO connected to a noise generator.  $C_{IN}$  and  $R_{IN}$  is the device, and any other stray or added capacitance or resistance across the A or B pin to GND2.  $C_{ISO}$  and  $R_{ISO}$  is the capacitance and resistance between GND1 and GND2 of the ISO1176, plus those of any other insulation (transformer, etc.). Stray inductance is assumed to be negligible.

From this model, the voltage at the isolated bus return is

$$V_{GND2} = V_N \frac{Z_{ISO}}{Z_{ISO} + Z_{IN}} \quad (1)$$

and will always be less than 16 V from  $V_N$ . If the ISO1176 is tested as a stand-alone device,

- $R_{IN} = 6 \times 10^4 \Omega$ ,
- $C_{IN} = 16 \times 10^{-12} \text{ F}$ ,
- $R_{ISO} = 10^9 \Omega$  and
- $C_{ISO} = 10^{-12} \text{ F}$ .

Notice from Figure 29 that the resistor ratio determines the voltage ratio at low frequencies, and that the inverse capacitance ratio determines the voltage ratio at high frequencies. In the stand-alone case and for low frequencies,

$$\frac{V_{GND2}}{V_N} = \frac{R_{ISO}}{R_{ISO} + R_{IN}} = \frac{10^9}{10^9 + 6 \times 10^4} \quad (2)$$

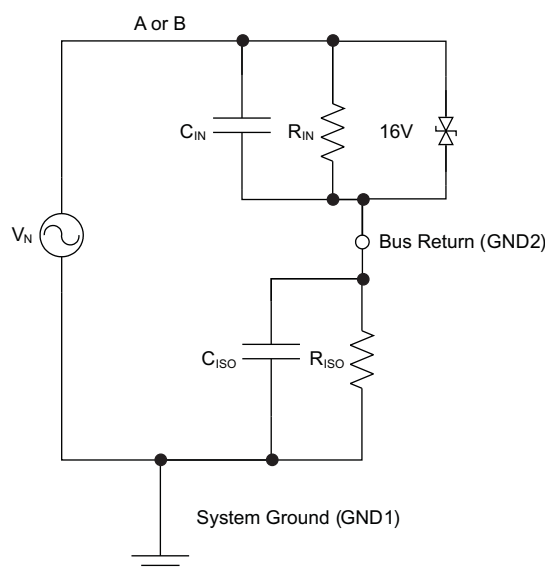
, or essentially all of the noise appears across the barrier.

At very high frequencies,

$$\frac{V_{GND2}}{V_N} = \frac{1/C_{ISO}}{1/C_{ISO} + 1/C_{IN}} = \frac{1}{1 + C_{ISO}/C_{IN}} = \frac{1}{1 + 1/16} = 0.94 \quad (3)$$

, and 94% of  $V_N$  appears across the barrier. As long as  $R_{ISO}$  is greater than  $R_{IN}$  and  $C_{ISO}$  is less than  $C_{IN}$ , most of the transient noise appears across the isolation barrier, as it should.

We do not recommend using ESD generators to test equipment transient susceptibility, or considering product claims of ESD ratings above the barrier transient ratings of an isolated interface. ESD is best managed through recessing or covering connector pins in a conductive connector shell, and by proper installer training.



**Figure 29. Device Model For Static Discharge Testing**

**PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
ISO1176DW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
ISO1176DWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBsolete:** TI has discontinued the production of the device.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

**Green (RoHS & no Sb/Br):** TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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**TAPE AND REEL INFORMATION**



**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO1176DWR	SOIC	DW	16	2000	330.0	16.4	10.9	10.78	3.0	12.0	16.0	Q1

**TAPE AND REEL BOX DIMENSIONS**

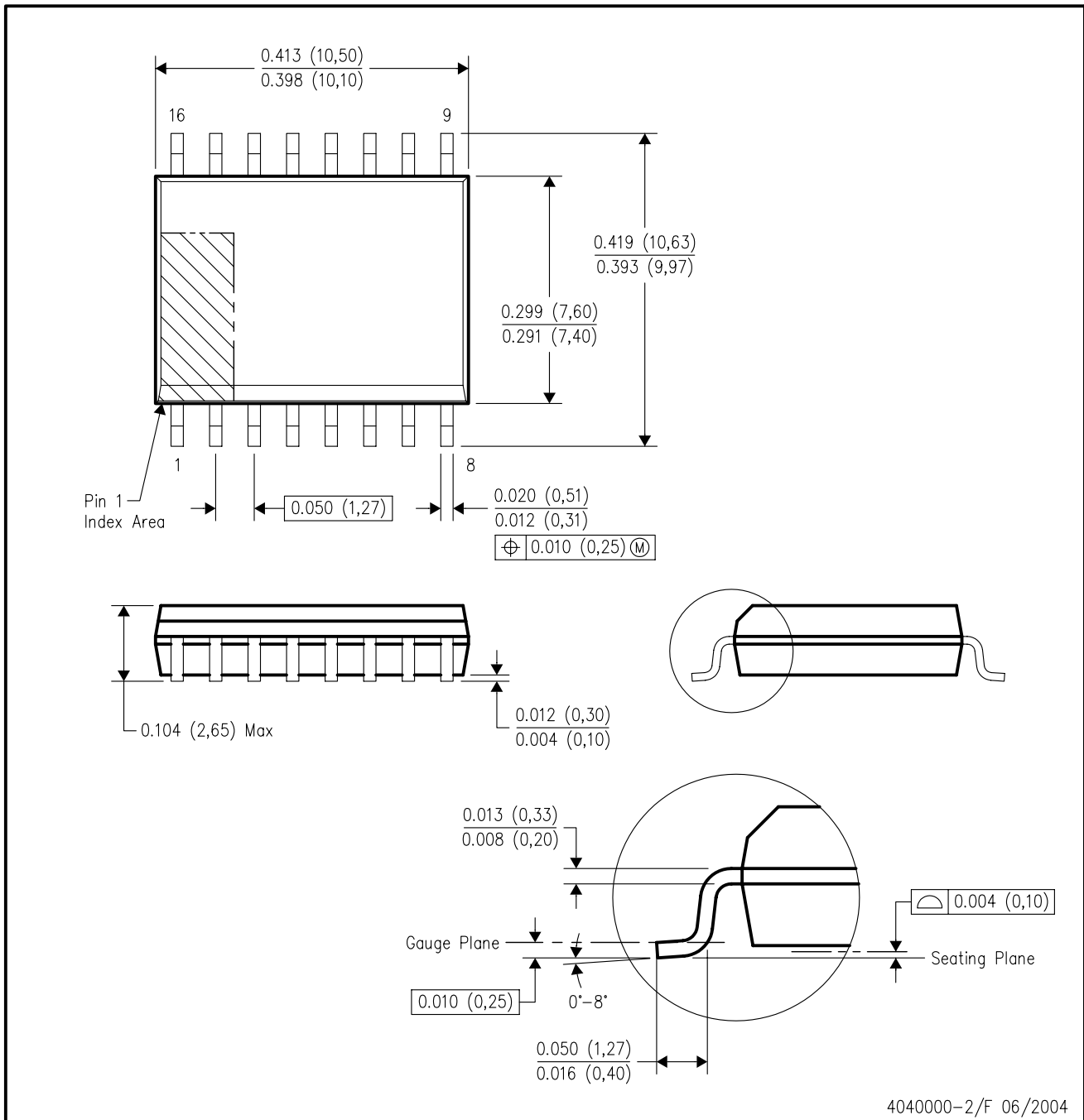


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO1176DWR	SOIC	DW	16	2000	358.0	335.0	35.0

DW (R-PDSO-G16)

PLASTIC SMALL-OUTLINE PACKAGE



- NOTES:
- A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
  - D. Falls within JEDEC MS-013 variation AA.



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